# Renesas 4 O/P 1.5V PCle Gen1-2-3 ZDB/FOB $w / Z o=1000 \mathrm{hms}$ 

## Description

The 9DBU0441 is a member of IDT's 1.5 V Ultra-Low-Power (ULP) PCle family. It has integrated output terminations providing $\mathrm{Zo}=100 \Omega$ for direct connection to $100 \Omega$ transmission lines. The device has 4 output enables for clock management, and 3 selectable SMBus addresses.

## Recommended Application

1.5V PCle Gen1-2-3 Zero-Delay/Fan-out Buffer (ZDB/FOB)

## Output Features

- 4 - 1-167MHz Low-Power (LP) HCSL DIF pairs $w / Z O=100 \Omega$


## Key Specifications

- DIF cycle-to-cycle jitter <50ps
- DIF output-to-output skew <75ps
- DIF phase jitter is PCle Gen1-2-3 compliant
- DIF bypass mode additive phase jitter is $<300 \mathrm{fs}$ rms for PCle Gen3
- DIF bypass mode additive phase jitter <350fs rms for 12k-20MHz


## Features/Benefits

- Direct connection to $100 \Omega$ transmission lines; saves 16 resistors compared to standard HCSL outputs
- 45 mW typical power consumption in PLL mode; eliminates thermal concerns
- Spread Spectrum (SS) compatible; allows SS for EMI reduction
- OE\# pins; support DIF power management
- HCSL-compatible differential input; can be driven by common clock sources
- SMBus-selectable features; optimize signal integrity to application
- slew rate for each output
- differential output amplitude
- Pin/software selectable PLL bandwidth and PLL Bypass; optimize PLL to application
- Outputs blocked until PLL is locked; clean system start-up
- Device contains default configuration; SMBus interface not required for device control
- 3.3V tolerant SMBus interface works with legacy controllers
- Three selectable SMBus addresses; multiple devices can easily share an SMBus segment
- Space saving 32-pin $5 \times 5 \mathrm{~mm}$ VFQFPN; minimal board space


## Block Diagram



## Pin Configuration



## 32-pin VFQFPN, $5 \times 5 \mathrm{~mm}, 0.5 \mathrm{~mm}$ pitch

$\wedge$ prefix indicates internal 120KOhm pull up resistor
$\wedge v$ prefix indicates internal 120KOhm pull up AND pull down resistor (biased to VDD/2)
v prefix indicates internal 120KOhm pull down resistor

## SMBus Address Selection Table

|  | SADR | Address | $\boldsymbol{+}$ |
| :---: | :---: | :---: | :---: |
| State ofRead/Write bit <br> SADR on first application of <br> CKPWRGD_PD\# O | 1101011 | x |  |
|  | M | 1101100 | x |
|  | 1 | 1101101 | x |

## Power Management Table

| CKPWRGD_PD\# | CLK_IN | SMBus <br> OEx bit | OEx\# Pin | DIFx |  | PLL |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | Comp. O/P |  |  |
| 0 | X | X | X | Low | Low | Off |
| 1 | Running | 0 | X | Low | Low | On $^{1}$ |
| 1 | Running | 1 | 0 | Running | Running | On $^{1}$ |
| 1 | Running | 1 | 1 | Low | Low | On $^{1}$ |

1. If Bypass mode is selected, the PLL will be off, and outputs will be running.

## Power Connections

| Pin Number |  | Description |
| :---: | :---: | :---: |
| VDD | GND |  |
| 4 | 7 | Input receiver analog |
| 9 | 8 | Digital Power |
| 16,25 | $15,20,26,30$ | DIF outputs |
| 21 | 20 | PLL Analog |

Note: epad on this device is not electrically connected to the die. It should be connected to ground for best thermal performance.

## PLL Operating Mode

| HiBW_BypM_LoBW\# | MODE | Byte1 [7:6] <br> Readback | Byte1 [4:3] <br> Control |
| :---: | :---: | :---: | :---: |
| 0 | PLL Lo BW | 00 | 00 |
| M | Bypass | 01 | 01 |
| 1 | PLL Hi BW | 11 | 11 |

## Pin Descriptions

| Pin\# | Pin Name | Type | Pin Description |
| :---: | :---: | :---: | :---: |
| 1 | ^vHIBW_BYPM_LOB | $\begin{aligned} & \text { LATCHED } \\ & \text { IN } \end{aligned}$ | Trilevel input to select High BW, Bypass or Low BW mode. See PLL Operating Mode Table for Details. |
| 2 | FB_DNC | DNC | True clock of differential feedback. The feedback output and feedback input are connected internally on this pin. Do not connect anything to this pin. |
| 3 | FB_DNC\# | DNC | Complement clock of differential feedback. The feedback output and feedback input are connected internally on this pin. Do not connect anything to this pin. |
| 4 | VDDR1.5 | PWR | 1.5 V power for differential input clock (receiver). This VDD should be treated as an Analog power rail and filtered appropriately. |
| 5 | CLK_IN | IN | True Input for differential reference clock. |
| 6 | CLK_IN\# | IN | Complementary Input for differential reference clock. |
| 7 | GNDR | GND | Analog Ground pin for the differential input (receiver) |
| 8 | GNDDIG | GND | Ground pin for digital circuitry |
| 9 | VDDDIG1.5 | PWR | 1.5 V digital power (dirty power) |
| 10 | SCLK_3.3 | IN | Clock pin of SMBus circuitry, 3.3V tolerant. |
| 11 | SDATA_3.3 | 1/O | Data pin for SMBus circuitry, 3.3V tolerant. |
| 12 | vOEO\# | IN | Active low input for enabling DIF pair 0 . This pin has an internal pull-down. <br> 1 =disable outputs, $0=$ enable outputs |
| 13 | DIF0 | OUT | Differential true clock output |
| 14 | DIFO\# | OUT | Differential Complementary clock output |
| 15 | GND | GND | Ground pin. |
| 16 | VDDO1.5 | PWR | Power supply for outputs, nominally 1.5 V . |
| 17 | vOE1\# | IN | Active low input for enabling DIF pair 1. This pin has an internal pull-down. 1 =disable outputs, $0=$ enable outputs |
| 18 | DIF1 | OUT | Differential true clock output |
| 19 | DIF1\# | OUT | Differential Complementary clock output |
| 20 | GNDA | GND | Ground pin for the PLL core. |
| 21 | VDDA1.5 | PWR | 1.5 V power for the PLL core. |
| 22 | DIF2 | OUT | Differential true clock output |
| 23 | DIF2\# | OUT | Differential Complementary clock output |
| 24 | vOE2\# | IN | Active low input for enabling DIF pair 2. This pin has an internal pull-down. 1 =disable outputs, $0=$ enable outputs |
| 25 | VDDO1.5 | PWR | Power supply for outputs, nominally 1.5 V . |
| 26 | GND | GND | Ground pin. |
| 27 | DIF3 | OUT | Differential true clock output |
| 28 | DIF3\# | OUT | Differential Complementary clock output |
| 29 | vOE3\# | IN | Active low input for enabling DIF pair 3. This pin has an internal pull-down. 1 =disable outputs, $0=$ enable outputs |
| 30 | GND | GND | Ground pin. |
| 31 | ^CKPWRGD_PD\# | IN | Input notifies device to sample latched inputs and start up on first high assertion. Low enters Power Down Mode, subsequent high assertions exit Power Down Mode. This pin has internal pull-up resistor. |
| 32 | ^SADR_tri | $\begin{gathered} \hline \text { LATCHED } \\ \text { IN } \end{gathered}$ | Tri-level latch to select SMBus Address. See SMBus Address Selection Table. |
| 33 | EPAD | GND | Connect ePAD to ground. |

## Test Loads



Note: The device can drive transmission line lengths greater than those allowed by the PCle SIG

## Driving LVDS



## Driving LVDS inputs

| Component | Value |  | Note |
| :---: | :---: | :---: | :---: |
|  | Receiver has termination | Receiver does not have termination |  |
| R7a, R7b | 10K ohm | 140 ohm |  |
| R8a, R8b | 5.6 K ohm | 75 ohm |  |
| Cc | 0.1 uF | 0.1 uF |  |
| Vcm | 1.2 volts | 1.2 volts |  |

## Absolute Maximum Ratings

Stresses above the ratings listed below can cause permanent damage to the 9DBU0441. These ratings, which are standard values for IDT commercially rated parts, are stress ratings only. Functional operation of the device at these or any other conditions above those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods can affect product reliability. Electrical parameters are guaranteed only over the recommended operating temperature range.

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Supply Voltage | VDDx |  | -0.5 |  | 2 | V | 1,2 |
| Input Voltage | $\mathrm{V}_{\text {IN }}$ |  | -0.5 |  | $\mathrm{~V}_{\mathrm{DD}}+0.5$ | V | 1,3 |
| Input High Voltage, SMBus | $\mathrm{V}_{\text {IHSMB }}$ | SMBus clock and data pins |  |  | 3.3 | V | 1 |
| Storage Temperature | Ts |  | -65 |  | 150 | ${ }^{\circ} \mathrm{C}$ | 1 |
| Junction Temperature | Tj |  |  |  | 125 | ${ }^{\circ} \mathrm{C}$ | 1 |
| Input ESD protection | ESD prot | Human Body Model | 2000 |  |  | V | 1 |

${ }^{1}$ Guaranteed by design and characterization, not $100 \%$ tested in production.
${ }^{2}$ Operation under these conditions is neither implied nor guaranteed.
${ }^{3}$ Not to exceed 2.0V.

## Electrical Characteristics-Clock Input Parameters

$T A=T_{\text {AMB }}$, Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Input Common Mode <br> Voltage - DIF_IN | $\mathrm{V}_{\text {COM }}$ | Common Mode Input Voltage | 200 |  | 725 | mV | 1 |
| Input Swing - DIF_IN | $\mathrm{V}_{\text {SWING }}$ | Differential value | 300 |  | 1450 | mV | 1 |
| Input Slew Rate - DIF_IN | $\mathrm{dV} / \mathrm{dt}$ | Measured differentially | 0.4 |  | 8 | $\mathrm{~V} / \mathrm{ns}$ | 1,2 |
| Input Leakage Current | $\mathrm{I}_{\mathrm{IN}}$ | $\mathrm{V}_{\text {IN }}=\mathrm{V}_{\text {DD }}, \mathrm{V}_{\text {IN }}=$ GND | -5 |  | 5 | uA |  |
| Input Duty Cycle | $\mathrm{d}_{\text {tin }}$ | Measurement from differential wavefrom | 45 | 50 | 55 | $\%$ | 1 |
| Input Jitter - Cycle to Cycle | $\mathrm{J}_{\text {DIFIn }}$ | Differential Measurement | 0 |  | 150 | ps | 1 |

[^0]
## Electrical Characteristics-Input/Supply/Common Parameters-Normal Operating Conditions

$\mathrm{TA}=\mathrm{T}_{\text {AMB }}$; Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Supply Voltage | VDDx | Supply voltage for core and analog | 1.425 | 1.5 | 1.575 | V |  |
| Ambient Operating Temperature | $\mathrm{T}_{\text {AMB }}$ | Commmercial range | 0 | 25 | 70 | ${ }^{\circ} \mathrm{C}$ | 1 |
|  |  | Industrial range | -40 | 25 | 85 | ${ }^{\circ} \mathrm{C}$ | 1 |
| Input High Voltage | $\mathrm{V}_{\text {IH }}$ | Single-ended inputs, except SMBus | $0.75 \mathrm{~V}_{\mathrm{DD}}$ |  | $\mathrm{V}_{\mathrm{DD}}+0.3$ | V |  |
| Input Mid Voltage | $\mathrm{V}_{\text {IM }}$ | Single-ended tri-level inputs ('_tri' suffix) | $0.4 \mathrm{~V}_{\mathrm{DD}}$ |  | $0.6 \mathrm{~V}_{\mathrm{DD}}$ | V |  |
| Input Low Voltage | $\mathrm{V}_{\text {IL }}$ | Single-ended inputs, except SMBus | -0.3 |  | $0.25 \mathrm{~V}_{\mathrm{DD}}$ | V |  |
| Input Current | $\mathrm{I}_{\text {IN }}$ | Single-ended inputs, $\mathrm{V}_{\text {IN }}=\mathrm{GND}, \mathrm{V}_{\text {IN }}=$ VDD | -5 |  | 5 | uA |  |
|  | 1 INP | Single-ended inputs <br> $\mathrm{V}_{\text {IN }}=0 \mathrm{~V}$; Inputs with internal pull-up resistors $\mathrm{V}_{\text {IN }}=$ VDD; Inputs with internal pull-down resistors | -200 |  | 200 | uA |  |
| Input Frequency | $\mathrm{F}_{\text {ibyp }}$ | Bypass mode | 1 |  | 167 | MHz | 2 |
|  | $\mathrm{F}_{\text {ipll }}$ | 100MHz PLL mode | 60 | 100.00 | 110 | MHz | 2 |
| Pin Inductance | $\mathrm{L}_{\text {pin }}$ |  |  |  | 7 | nH | 1 |
| Capacitance | $\mathrm{C}_{\text {IN }}$ | Logic Inputs, except DIF_IN | 1.5 |  | 5 | pF | 1 |
|  | $\mathrm{C}_{\text {INDIF,IN }}$ | DIF_IN differential clock inputs | 1.5 |  | 2.7 | pF | 1,5 |
|  | $\mathrm{C}_{\text {OUT }}$ | Output pin capacitance |  |  | 6 | pF | 1 |
| Clk Stabilization | $\mathrm{T}_{\text {Stab }}$ | From $\mathrm{V}_{\mathrm{DD}}$ Power-Up and after input clock stabilization or de-assertion of PD\# to 1st clock |  |  | 1 | ms | 1,2 |
| Input SS Modulation Frequency PCle | $\mathrm{f}_{\text {MODINPCle }}$ | Allowable Frequency for PCle Applications (Triangular Modulation) | 30 |  | 33 | kHz |  |
| Input SS Modulation Frequency non-PCle | $\mathrm{f}_{\text {MODIN }}$ | Allowable Frequency for non-PCle Applications (Triangular Modulation) | 0 |  | 66 | kHz |  |
| OE\# Latency | $\mathrm{t}_{\text {Latoe }}$ | DIF start after OE\# assertion DIF stop after OE\# deassertion | 1 |  | 3 | clocks | 1,3 |
| Tdrive_PD\# | $\mathrm{t}_{\text {DRVPD }}$ | DIF output enable after PD\# de-assertion |  |  | 300 | us | 1,3 |
| Tfall | $\mathrm{t}_{\mathrm{F}}$ | Fall time of single-ended control inputs |  |  | 5 | ns | 2 |
| Trise | $\mathrm{t}_{\mathrm{R}}$ | Rise time of single-ended control inputs |  |  | 5 | ns | 2 |
| SMBus Input Low Voltage | $\mathrm{V}_{\text {ILSMB }}$ |  |  |  | 0.6 | V |  |
| SMBus Input High Voltage | $\mathrm{V}_{\text {IHSMB }}$ | $\mathrm{V}_{\text {DDSMB }}=3.3 \mathrm{~V}$, see note 4 for $\mathrm{V}_{\text {DDSMB }}<3.3 \mathrm{~V}$ | 2.1 |  | 3.3 | V | 4 |
| SMBus Output Low Voltage | $\mathrm{V}_{\text {OLSMB }}$ | @ IPULLUP |  |  | 0.4 | V |  |
| SMBus Sink Current | IpULLUP | @ $\mathrm{V}_{\mathrm{OL}}$ | 4 |  |  | mA |  |
| Nominal Bus Voltage | $\mathrm{V}_{\text {DDSMB }}$ | Bus Voltage | 1.425 |  | 3.3 | V |  |
| SCLK/SDATA Rise Time | $\mathrm{t}_{\text {RSMB }}$ | (Max VIL - 0.15) to (Min VIH + 0.15) |  |  | 1000 | ns | 1 |
| SCLK/SDATA Fall Time | $\mathrm{t}_{\text {FSMB }}$ | (Min VIH + 0.15) to (Max VIL - 0.15) |  |  | 300 | ns | 1 |
| SMBus Operating Frequency | $\mathrm{f}_{\text {MAXSMB }}$ | Maximum SMBus operating frequency |  |  | 400 | kHz | 6 |

${ }^{1}$ Guaranteed by design and characterization, not $100 \%$ tested in production.
${ }^{2}$ Control input must be monotonic from $20 \%$ to $80 \%$ of input swing.
${ }^{3}$ Time from deassertion until outputs are $>200 \mathrm{mV}$
${ }^{4}$ For $V_{\text {DDSMB }}<3.3 V, V_{\text {IHSMB }}>=0.8 x V_{\text {DDSMB }}$
${ }^{5}$ DIF_IN input
${ }^{6}$ The differential input clock must be running for the SMBus to be active

## Electrical Characteristics-Low-Power HCSL Outputs

$\mathrm{TA}=\mathrm{T}_{\mathrm{AMB}}$; Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Slew rate | dV/dt | Scope averaging on, fast setting (100MHz) | 1 | 2.4 | 3.5 | V/ns | 1,2,3 |
|  | $\mathrm{dV} / \mathrm{dt}$ | Scope averaging on, slow setting (100MHz) | 0.7 | 1.7 | 2.5 | V/ns | 1,2,3 |
| Slew rate matching | $\Delta \mathrm{dV} / \mathrm{dt}$ | Slew rate matching, Scope averaging on |  | 9 | 20 | \% | 1,2,4 |
| Voltage High | $\mathrm{V}_{\text {HIGH }}$ | Statistical measurement on single-ended signal using oscilloscope math function. (Scope averaging on) | 630 | 750 | 850 | mV | 7 |
| Voltage Low | $V_{\text {Low }}$ |  | -150 | 26 | 150 |  | 7 |
| Max Voltage | Vmax | Measurement on single ended signal using absolute value. (Scope averaging off) |  | 763 | 1150 | mV | 7 |
| Min Voltage | $V$ min |  | -300 | 22 |  |  | 7 |
| Vswing | Vswing | Scope averaging off | 300 | 1448 |  | mV | 1,2 |
| Crossing Voltage (abs) | Vcross_abs | Scope averaging off | 250 | 390 | 550 | mV | 1,5 |
| Crossing Voltage (var) | $\Delta$-Vcross | Scope averaging off |  | 11 | 140 | mV | 1,6 |

${ }^{1}$ Guaranteed by design and characterization, not $100 \%$ tested in production.
${ }^{2}$ Measured from differential waveform
${ }^{3}$ Slew rate is measured through the Vswing voltage range centered around differential $0 V$. This results in $a+/-150 \mathrm{mV}$ window around differential OV.
${ }^{4}$ Matching applies to rising edge rate for Clock and falling edge rate for Clock\#. It is measured using a $+/-75 \mathrm{mV}$ window centered on the average cross point where Clock rising meets Clock\# falling. The median cross point is used to calculate the voltage thresholds the oscilloscope is to use for the edge rate calculations.
${ }^{5}$ Vcross is defined as voltage where Clock = Clock\# measured on a component test board and only applies to the differential rising edge (i.e. Clock rising and Clock\# falling).
${ }^{6}$ The total variation of all Vcross measurements in any particular system. Note that this is a subset of Vcross_min/max (Vcross absolute) allowed. The intent is to limit Vcross induced modulation by setting $\Delta$-Vcross to be smaller than Vcross absolute.
${ }^{7}$ At default SMBus settings.

## Electrical Characteristics-Current Consumption

TA $=\mathrm{T}_{\text {AMB }}$; Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Operating Supply Current | $\mathrm{I}_{\text {DDR }}$ | VDDR @ 100MHz |  | 4 | 6 | mA | 1 |
|  | $\mathrm{I}_{\text {DDDIG }}$ | VDDIG, All outputs @ 100MHz |  | 0.125 | 0.25 | mA | 1 |
|  | $\mathrm{I}_{\text {DDAO }}$ | VDDA+VDDO, PLL Mode, All outputs @ 100MHz |  | 25 | 30 | mA | 1 |
| Powerdown Current | $\mathrm{I}_{\text {DDRPD }}$ | VDDR, CKPWRGD_PD\# = 0 |  | 0.1 | 0.3 | mA | 1,2,3 |
|  | $\mathrm{I}_{\text {DDDIGPD }}$ | VDDDIG, CKPWRGD_PD\# = 0 |  | 0.1 | 0.2 | mA | 1,2 |
|  | IDDAOPD | VDDA+VDDO, CKPWRGD_PD\# = 0 |  | 0.5 | 1 | mA | 1,2 |

[^1]
## Electrical Characteristics-Output Duty Cycle, Jitter, Skew and PLL Characteristics

$T A=T_{\text {AMB }}$; Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| PLL Bandwidth | BW | -3dB point in High BW Mode (100MHz) | 2.3 | 3.6 | 4.7 | MHz | 1,5 |
|  |  | -3dB point in Low BW Mode (100MHz) | 1 | 1.6 | 2.5 | MHz | 1,5 |
| PLL Jitter Peaking | $\mathrm{t}_{\text {JPEAK }}$ | Peak Pass band Gain (100MHz) |  | 1.3 | 2.5 | dB | 1 |
| Duty Cycle | $\mathrm{t}_{\mathrm{DC}}$ | Measured differentially, PLL Mode | 45 | 50 | 55 | \% | 1 |
| Duty Cycle Distortion | $t_{\text {DCD }}$ | Measured differentially, Bypass Mode @100MHz | -1 | -0.6 | 0 | \% | 1,3 |
| Skew, Input to Output | $\mathrm{t}_{\text {pdBYP }}$ | Bypass Mode, $\mathrm{V}_{\mathrm{T}}=50 \%$ | 3400 | 4301 | 5200 | ps | 1 |
|  | $\mathrm{t}_{\mathrm{pdPLL}}$ | PLL Mode $\mathrm{V}_{\mathrm{T}}=50 \%$ | 0 | 50 | 150 | ps | 1,4 |
| Skew, Output to Output | $\mathrm{t}_{\text {sk3 }}$ | $\mathrm{V}_{\mathrm{T}}=50 \%$ |  | 37 | 50 | ps | 1,4 |
| Jitter, Cycle to cycle | $\mathrm{t}_{\text {jcyc-cyc }}$ | PLL mode |  | 24 | 50 | ps | 1,2 |
|  |  | Additive Jitter in Bypass Mode |  | 0.1 | 5 | ps | 1,2 |

${ }^{1}$ Guaranteed by design and characterization, not $100 \%$ tested in production.
${ }^{2}$ Measured from differential waveform
${ }^{3}$ Duty cycle distortion is the difference in duty cycle between the output and the input clock when the device is operated in bypass mode.
${ }^{4}$ All outputs at default slew rate
${ }^{5}$ The MIN/TYP/MAX values of each BW setting track each other, i.e., Low BW MAX will never occur with Hi BW MIN.

## Electrical Characteristics-Phase Jitter Parameters

$\mathrm{TA}=\mathrm{T}_{\text {AMB }}$; Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | INDUSTRY LIMIT | UNITS | Notes |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Phase Jitter, PLL Mode | $\mathrm{t}_{\text {jphPCleG1 }}$ | PCle Gen 1 |  | 30 | 58 | 86 | ps (p-p) | 1,2,3,5 |
|  | $\mathrm{t}_{\text {jphPCleG2 }}$ | PCle Gen 2 Lo Band $10 \mathrm{kHz}<\mathrm{f}<1.5 \mathrm{MHz}$ |  | 0.9 | 1.4 | 3 | $\begin{gathered} \mathrm{ps} \\ (\mathrm{rms}) \end{gathered}$ | 1,2,3,5 |
|  |  | PCle Gen 2 High Band $1.5 \mathrm{MHz}<\mathrm{f}<$ Nyquist ( 50 MHz ) |  | 2.1 | 2.6 | 3.1 | $\begin{gathered} \mathrm{ps} \\ (\mathrm{rms}) \end{gathered}$ | 1,2,3,5 |
|  | $\mathrm{t}_{\text {jphPCleG3Co }}$ <br> m | PCle Gen 3 Common Clock Architecture (PLL BW of $2-4$ or $2-5 \mathrm{MHz}, \mathrm{CDR}=10 \mathrm{MHz}$ ) |  | 0.5 | 0.6 | 1 | $\begin{gathered} \mathrm{ps} \\ (\mathrm{rms}) \end{gathered}$ | 1,2,3,5 |
|  | $\mathrm{t}_{\text {jphPCleG3SRn }} \mid$ <br> s | PCle Gen 3 Separate Reference No Spread (SRnS) (PLL BW of $2-4$ or $2-5 \mathrm{MHz}, \mathrm{CDR}=10 \mathrm{MHz}$ ) |  | 0.5 | 0.6 | 0.7 | $\begin{gathered} \mathrm{ps} \\ (\mathrm{rms}) \end{gathered}$ | 1,2,3,5 |
| Additive Phase Jitter, Bypass Mode | $\mathrm{t}_{\text {jphPCleG1 }}$ | PCle Gen 1 |  | 0.1 | 5 | N/A | ps (p-p) | 1,2,3,5 |
|  | $\mathrm{t}_{\text {jphPCleG2 }}$ | PCle Gen 2 Lo Band $10 \mathrm{kHz}<\mathrm{f}<1.5 \mathrm{MHz}$ |  | 0.1 | 0.5 | N/A | $\begin{gathered} \mathrm{ps} \\ (\mathrm{rms}) \end{gathered}$ | $\begin{gathered} \hline 1,2,3,4, \\ 5 \\ \hline \end{gathered}$ |
|  |  | PCle Gen 2 High Band $1.5 \mathrm{MHz}<\mathrm{f}<$ Nyquist ( 50 MHz ) |  | 0.1 | 0.3 | N/A | $\begin{gathered} \mathrm{ps} \\ (\mathrm{rms}) \end{gathered}$ | 1,2,3,4 |
|  | $\mathrm{t}_{\text {jphPCleG3 }}$ | PCle Gen 3 <br> (PLL BW of $2-4$ or $2-5 \mathrm{MHz}, \mathrm{CDR}=10 \mathrm{MHz}$ ) |  | 0.2 | 0.3 | N/A | $\begin{gathered} \mathrm{ps} \\ (\mathrm{rms}) \end{gathered}$ | 1,2,3,4 |
|  | $\mathrm{t}_{\text {jph125M0 }}$ | $125 \mathrm{MHz}, 1.5 \mathrm{MHz}$ to $10 \mathrm{MHz},-20 \mathrm{~dB} /$ decade rollover $<1.5 \mathrm{MHz},-40 \mathrm{db} /$ decade rolloff $>10 \mathrm{MHz}$ |  | 200 | 300 | N/A | $\begin{gathered} \mathrm{fs} \\ (\mathrm{rms}) \end{gathered}$ | 1,6 |
|  | $\mathrm{t}_{\text {jph125M1 }}$ | $125 \mathrm{MHz}, 12 \mathrm{KHz}$ to $20 \mathrm{MHz},-20 \mathrm{~dB} /$ decade rollover < $1.5 \mathrm{MHz},-40 \mathrm{db} /$ decade rolloff $>10 \mathrm{MHz}$ |  | 313 | 350 | N/A | $\begin{gathered} \mathrm{fs} \\ (\mathrm{rms}) \end{gathered}$ | 1,6 |

[^2]
## Additive Phase Jitter Plot: 125M (12kHz to 20MHz)

## Agilent E5052A Signal Source Analyzer



## General SMBus Serial Interface Information

## How to Write

- Controller (host) sends a start bit
- Controller (host) sends the write address
- IDT clock will acknowledge
- Controller (host) sends the beginning byte location $=\mathrm{N}$
- IDT clock will acknowledge
- Controller (host) sends the byte count = X
- IDT clock will acknowledge
- Controller (host) starts sending Byte $\mathbf{N}$ through Byte $\mathrm{N}+\mathrm{X}-1$
- IDT clock will acknowledge each byte one at a time
- Controller (host) sends a Stop bit

| Index Block Write Operation |  |  |
| :---: | :---: | :---: |
| Controller (Host) |  | IDT (Slave/Receiver) |
| T | starT bit |  |
| Slave Address |  |  |
| WR | WRite |  |
|  |  | ACK |
| Beginning Byte $=\mathrm{N}$ |  |  |
|  |  | ACK |
| Data Byte Count = X |  |  |
|  |  | ACK |
| Beginning Byte N |  |  |
|  |  | ACK |
| 0 |  |  |
| 0 |  | 0 |
| 0 |  | 0 |
|  |  | 0 |
| Byte N+X-1 |  |  |
|  |  | ACK |
| P | stoP bit |  |

Note: SMBus Address is Latched on SADR pin.

## How to Read

- Controller (host) will send a start bit
- Controller (host) sends the write address
- IDT clock will acknowledge
- Controller (host) sends the beginning byte location $=\mathrm{N}$
- IDT clock will acknowledge
- Controller (host) will send a separate start bit
- Controller (host) sends the read address
- IDT clock will acknowledge
- IDT clock will send the data byte count $=X$
- IDT clock sends Byte N+X-1
- IDT clock sends Byte 0 through Byte $\mathbf{X}$ (if $X_{(H)}$ was written to Byte 8)
- Controller (host) will need to acknowledge each byte
- Controller (host) will send a not acknowledge bit
- Controller (host) will send a stop bit

| Index Block Read Operation |  |  |  |
| :---: | :---: | :---: | :---: |
| Controller (Host) |  |  | IDT (Slave/Receiver) |
| T | starT bit |  |  |
| Slave Address |  |  |  |
| WR | WRite |  |  |
|  |  |  | ACK |
| Beginning Byte $=\mathrm{N}$ |  |  |  |
|  |  |  | ACK |
| RT | Repeat starT |  |  |
| Slave Address |  |  |  |
| RD | ReaD |  |  |
|  |  |  | ACK |
|  |  |  |  |
|  |  |  | Data Byte Count=X |
| ACK |  |  |  |
|  |  |  | Beginning Byte N |
| ACK |  |  |  |
|  |  |  | 0 |
|  | 0 |  | 0 |
| 0 |  |  | 0 |
| 0 |  |  |  |
|  |  |  | Byte $\mathrm{N}+\mathrm{X}-1$ |
| N | Not acknowledge |  |  |
| P | stoP bit |  |  |

SMBus Table: Output Enable Register ${ }^{1}$

| Byte 0 | Name | Control Function | Type | 0 | 1 | Default |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Bit 7 | Reserved |  |  |  |  | 1 |
| Bit 6 | DIF OE3 | Output Enable | RW | Low/Low | Enabled | 1 |
| Bit 5 | DIF OE2 | Output Enable | RW | Low/Low | Enabled | 1 |
| Bit 4 | Reserved |  |  |  |  | 1 |
| Bit 3 | DIF OE1 | Output Enable | RW | Low/Low | Enabled | 1 |
| Bit 2 | Reserved |  |  |  |  | 1 |
| Bit 1 | DIF OE0 | Output Enable | RW | Low/Low | Enabled | 1 |
| Bit 0 | Reserved |  |  |  |  | 1 |

1. A low on these bits will overide the OE\# pin and force the differential output Low/Low

SMBus Table: PLL Operating Mode and Output Amplitude Control Register

| Byte 1 | Name | Control Function | Type | 0 | 1 | Default |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Bit 7 | PLLMODERB1 | PLL Mode Readback Bit 1 | R | See PLL Operating Mode Table |  | Latch |
| Bit 6 | PLLMODERB0 | PLL Mode Readback Bit 0 | R |  |  | Latch |
| Bit 5 | PLLMODE_SWCNTRL | Enable SW control of PLL Mode | RW | ```Values in B1[7:6] set PLL Mode``` | Values in B1[4:3] set PLL Mode | 0 |
| Bit 4 | PLLMODE1 | PLL Mode Control Bit 1 | RW ${ }^{1}$ | See PLL Operating Mode Table |  | 0 |
| Bit 3 | PLLMODE0 | PLL Mode Control Bit 0 | RW ${ }^{1}$ |  |  | 0 |
| Bit 2 | Reserved |  |  |  |  | 1 |
| Bit 1 | AMPLITUDE 1 | Controls Output Amplitude | RW | $00=0.55 \mathrm{~V}$ | $01=0.65 \mathrm{~V}$ | 1 |
| Bit 0 | AMPLITUDE 0 |  | RW | $10=0.75 \mathrm{~V}$ | $11=0.85 \mathrm{~V}$ | 0 |

1. B1[5] must be set to a 1 for these bits to have any effect on the part.

SMBus Table: DIF Slew Rate Control Register

| Byte 2 | Name | Control Function | Type | 0 | 1 | Default |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Bit 7 | Reserved |  |  |  |  | 1 |
| Bit 6 | SLEWRATESEL DIF3 | Slew Rate Selection | RW | Slow Setting | Fast Setting | 1 |
| Bit 5 | SLEWRATESEL DIF2 | Slew Rate Selection | RW | Slow Setting | Fast Setting | 1 |
| Bit 4 | Reserved |  |  |  |  | 1 |
| Bit 3 | SLEWRATESEL DIF1 | Slew Rate Selection | RW | Slow Setting | Fast Setting | 1 |
| Bit 2 | Reserved |  |  |  |  | 1 |
| Bit 1 | SLEWRATESEL DIF0 | Slew Rate Selection | RW | Slow Setting | Fast Setting | 1 |
| Bit 0 | Reserved |  |  |  |  | 1 |

SMBus Table: Frequency Select Control Register

| Byte 3 | Name | Control Function | Type | 0 | 1 | Default |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Bit 7 | Reserved |  |  |  |  | 1 |
| Bit 6 | Reserved |  |  |  |  | 1 |
| Bit 5 | Reserved |  |  |  |  | 0 |
| Bit 4 | Reserved |  |  |  |  | 0 |
| Bit 3 | Reserved |  |  |  |  | 0 |
| Bit 2 | Reserved |  |  |  |  | 1 |
| Bit 1 | Reserved |  |  |  |  | 1 |
| Bit 0 | SLEWRATESEL FB | Adjust Slew Rate of FB | RW | Slow Setting | Fast Setting | 1 |

Byte 4 is Reserved and reads back 'hFF

SMBus Table: Revision and Vendor ID Register

| Byte 5 | Name | Control Function | Type | 0 | Default |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Bit 7 | RID3 | Revision ID | R |  | 0 |
| Bit 6 | RID2 |  | R |  | 0 |
| Bit 5 | RID1 |  | R |  | 0 |
| Bit 4 | RID0 |  | R |  | 0 |
| Bit 3 | VID3 | VENDOR ID | R |  | 0 |
| Bit 2 | VID2 |  | R |  | 0 |
| Bit 1 | VID1 |  | R |  | 0 |
| Bit 0 | VID0 |  | R |  | 1 |

SMBus Table: Device Type/Device ID

| Byte 6 | Name | Control Function | Type | 0 0 1 | Default |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Bit 7 | Device Type1 | Device Type | R | $\begin{gathered} 00 \text { = FGx, } 01=\mathrm{DBx} \text { ZDB/FOB, } \\ 10=\mathrm{DMx}, 11=\mathrm{DBx} \text { FOB } \end{gathered}$ | 0 |
| Bit 6 | Device Type0 |  | R |  | 1 |
| Bit 5 | Device ID5 | Device ID | R | 000100 binary or 04 hex | 0 |
| Bit 4 | Device ID4 |  | R |  | 0 |
| Bit 3 | Device ID3 |  | R |  | 0 |
| Bit 2 | Device ID2 |  | R |  | 1 |
| Bit 1 | Device ID1 |  | R |  | 0 |
| Bit 0 | Device ID0 |  | R |  | 0 |

## SMBus Table: Byte Count Register

| Byte 7 | Name | Control Function | Type | 0 | 1 | Default |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Bit 7 |  | Reserved |  |  |  | 0 |
| Bit 6 |  | Reserved |  |  |  | 0 |
| Bit 5 |  | Reserved |  |  |  | 0 |
| Bit 4 | BC4 | Byte Count Programming | RW | Writing to this register will configure how many bytes will be read back, default is $=8$ bytes. |  | 0 |
| Bit 3 | BC3 |  | RW |  |  | 1 |
| Bit 2 | BC2 |  | RW |  |  | 0 |
| Bit 1 | BC1 |  | RW |  |  | 0 |
| Bit 0 | BC0 |  | RW |  |  | 0 |

## Marking Diagrams



Notes:

1. "LOT" is the lot sequence number.
2. "COO" denotes country of origin.
3. YYWW is the last two digits of the year and week that the part was assembled.
4. Line 2: truncated part number
5. "L" denotes RoHS compliant package.
6. "I" denotes industrial temperature range device.

## Thermal Characteristics

| PARAMETER | SYMBOL | CONDITIONS | PKG | TYP VALUE | UNITS | NOTES |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Thermal Resistance | $\theta_{\text {Jc }}$ | Junction to Case | NLG32 | 42 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ | 1 |
|  | $\theta_{\mathrm{Jb}}$ | Junction to Base |  | 2.4 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ | 1 |
|  | $\theta_{\text {JAO }}$ | Junction to Air, still air |  | 39 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ | 1 |
|  | $\theta_{\text {JA1 }}$ | Junction to Air, $1 \mathrm{~m} / \mathrm{s}$ air flow |  | 33 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ | 1 |
|  | $\theta_{\text {JA3 }}$ | Junction to Air, $3 \mathrm{~m} / \mathrm{s}$ air flow |  | 28 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ | 1 |
|  | $\theta_{\text {JA5 }}$ | Junction to Air, $5 \mathrm{~m} / \mathrm{s}$ air flow |  | 27 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ | 1 |

${ }^{1}$ ePad soldered to board

## Package Outline and Package Dimensions (NLG32) - use EPAD Option 1



## Ordering Information

| Part / Order Number | Shipping Packaging | Package | Temperature |
| :---: | :---: | :---: | :---: |
| 9DBU0441AKLF | Trays | 32-pin VFQFPN | 0 to $+70^{\circ} \mathrm{C}$ |
| 9DBU0441AKLFT | Tape and Reel | 32-pin VFQFPN | 0 to $+70^{\circ} \mathrm{C}$ |
| 9DBU0441AKILF | Trays | 32-pin VFQFPN | -40 to $+85^{\circ} \mathrm{C}$ |
| 9DBU0441AKILFT | Tape and Reel | 32-pin VFQFPN | -40 to $+85^{\circ} \mathrm{C}$ |

"LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.
" $A$ " is the device revision designator (will not correlate with the datasheet revision).

## Revision History

| Rev. | Initiator | Issue Date | Description | Page \# |
| :---: | :---: | :---: | :--- | :---: |
| A | RDW | $7 / 14 / 2014$ | 1. Updated electrical tables with char data. <br> 2. Added an additive phase jitter plot. <br> 3. Added 12 kHz to 20MHz additive phase jitter spec. <br> 4. Updated Amplitude control bit descriptions in Byte 1. | Various |
| B | RDW | $9 / 19 / 2014$ | Updated SMBus Input High/Low parameters conditions, MAX values, <br> and footnotes. | 6 |
| C | RDW | $4 / 17 / 2015$ | 1. Updated pin out and pin descriptions to show ePad on package <br> connected to ground. <br> 2. Updated front page text to standard format for these devices. Added <br> explicit bullet indicated Spread Spectrum compatibility. <br> 3. Updated Clock Input Parameters table to be consistent with PCle <br> Vswing parameter. <br> 4. Minor updates to front page text for family consistency. <br> 5. Add note about tpad to Power Connections table. | $1-5$ |



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[^0]:    ${ }^{1}$ Guaranteed by design and characterization, not $100 \%$ tested in production.
    ${ }^{2}$ Slew rate measured through $+/-75 \mathrm{mV}$ window centered around differential zero

[^1]:    ${ }^{1}$ Guaranteed by design and characterization, not $100 \%$ tested in production.
    ${ }^{2}$ Input clock stopped.
    ${ }^{3}$ In bypass mode, the PLL is off and IDDAO is $\sim 50 \%$ of this value.

[^2]:    ${ }^{1}$ Guaranteed by design and characterization, not $100 \%$ tested in production.
    ${ }^{2}$ See http://www.pcisig.com for complete specs
    ${ }^{3}$ Sample size of at least 100 K cycles. This figures extrapolates to $108 \mathrm{ps} \mathrm{pk}-\mathrm{pk} @ 1 \mathrm{M}$ cycles for a BER of 1-12.
    ${ }^{4}$ For RMS figures, additive jitter is calculated by solving the following equation: Additive jitter = SQRT[(total jitter)^2 - (input jitter)^2]
    ${ }^{5}$ Driven by 9FGU0831 or equivalent
    ${ }^{6}$ Rohde\&Schartz SMA100

